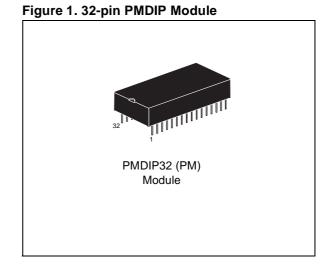


## 5.0 or 3.3V, 1 Mbit (128 Kb x 8) TIMEKEEPER<sup>®</sup> SRAM

#### FEATURES SUMMARY

- INTEGRATED, ULTRA LOW POWER SRAM, REAL TIME CLOCK, POWER-FAIL CONTROL CIRCUIT, BATTERY, and CRYSTAL
- BCD CODED YEAR, MONTH, DAY, DATE, HOURS, MINUTES, and SECONDS
- AUTOMATIC POWER-FAIL CHIP DESELECT and WRITE PROTECTION
- WRITE PROTECT VOLTAGES
   (V<sub>PFD</sub> = Power-fail Deselect Voltage):
  - M48T128Y: V<sub>CC</sub> = 4.5 to 5.5V 4.1V  $\leq$  V<sub>PFD</sub>  $\leq$  4.5V
  - M48T128V: V<sub>CC</sub> = 3.0 to 3.6V 2.7V  $\leq$  V<sub>PFD</sub>  $\leq$  3.0V
- CONVENTIONAL SRAM OPERATION; UNLIMITED WRITE CYCLES
- SOFTWARE CONTROLLED CLOCK CALIBRATION FOR HIGH ACCURACY APPLICATIONS
- 10 YEARS OF DATA RETENTION and CLOCK OPERATION IN THE ABSENCE OF POWER
- SELF-CONTAINED BATTERY and CRYSTAL IN THE DIP PACKAGE
- PIN and FUNCTION COMPATIBLE WITH JEDEC STANDARD 128K x 8 SRAMs



#### \* Contact Local Sales Office

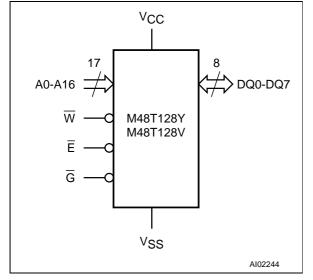
## TABLE OF CONTENTS

SUMMARY DESCRIPTION
Logic Diagram (Figure 2.)       3         Signal Names (Table 1.)       3         DIP Connections (Figure 3.)       3         Block Diagram (Figure 4.)       4
MAXIMUM RATING
Absolute Maximum Ratings (Table 2.)4
DC AND AC PARAMETERS
Operating and AC Measurement Conditions (Table 3.)       5         AC Testing Load Circuit (Figure 5.)       5         Capacitance (Table 4.)       5         DC Characteristics (Table 5.)       6
OPERATION MODES
Operating Modes (Table 6.)6READ Mode.7READ Mode AC Waveforms (Figure 6.)7READ Mode AC Characteristics (Table 7.)7WRITE Mode.8WRITE Enable Controlled, WRITE AC Waveform (Figure 7.)8Chip Enable Controlled, WRITE AC Waveforms (Figure 8.)8WRITE Mode AC Characteristics (Table 8.)9Data Retention Mode.10Power Down/Up Mode AC Waveforms (Figure 9.)10Power Down/Up AC Characteristics (Table 9.)10Power Down/Up Trip Points DC Characteristics (Table 10.)11
CLOCK OPERATIONS
Reading the Clock11Setting the Clock11Register Map (Table 11.)12Stopping and Starting the Oscillator11Calibrating the Clock12Crystal Accuracy Across Temperature (Figure 10.)13Clock Calibration (Figure 11.)13Vcc Noise And Negative Going Transients14Supply Voltage Protection (Figure 12.)14
PART NUMBERING
PACKAGE MECHANICAL INFORMATION
REVISION HISTORY

#### SUMMARY DESCRIPTION

The M48T128Y/V TIMEKEEPER<sup>®</sup> RAM is a 128Kb x 8 non-volatile static RAM and real time clock. The special DIP package provides a fully integrated battery back-up memory and real time clock solution. The M48T128Y/V directly replaces industry standard 128Kb x 8 SRAM.

#### Figure 2. Logic Diagram



#### **Figure 3. DIP Connections**

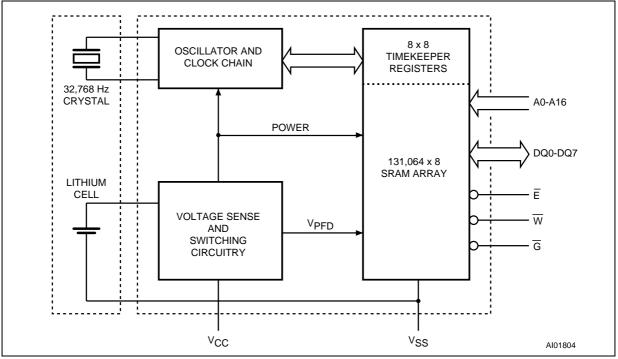
NC [	1	32 VCC
A16 [	2	31 🛛 A15
A14 [	3	30 🛛 NC
A12 [	4	29 🛛 ₩
A7 [	5	28 🛛 A13
A6 [	6	27 🛛 A8
A5 [	7	26 🛛 A9
A4 [		M48T128Y 25 🛛 A11
A3 [	9	M48T128V 24 ] G
A2 [	10	23 🛛 A10
A1 [	11	22 🛛 Ē
A0 [	12	21 🛛 DQ7
DQ0 [	13	20 🛛 DQ6
DQ1 [	14	19 🛛 DQ5
DQ2 [	15	18 🛛 DQ4
V <sub>SS</sub> [	16	17 ] DQ3
		AI02245

It also provides the non-volatility of Flash without any requirement for special WRITE timing or limitations on the number of WRITEs that can be performed. The 32-pin, 600mil DIP Hybrid houses a controller chip, SRAM, quartz crystal, and a long life lithium button cell in a single package.

i ale e i e gi	
A0-A16	Address Inputs
DQ0-DQ7	Data Inputs / Outputs
Ē	Chip Enable
G	Output Enable
W	WRITE Enable
V <sub>CC</sub>	Supply Voltage
V <sub>SS</sub>	Ground
NC	Not Connected Internally

#### **Table 1. Signal Names**

#### Figure 4. Block Diagram



#### MAXIMUM RATING

Stressing the device above the rating listed in the "Absolute Maximum Ratings" table may cause permanent damage to the device. These are stress ratings only and operation of the device at these or any other conditions above those indicated in the Operating sections of this specification is not implied. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability. Refer also to the STMicroelectronics SURE Program and other relevant guality documents.

**A7** 

#### **Table 2. Absolute Maximum Ratings**

Symbol	Parameter	Value	Unit	
T <sub>A</sub>	Ambient Operating Temperature		0 to 70	°C
T <sub>STG</sub>	Storage Temperature (V <sub>CC</sub> Off, Oscillator Off)		-40 to 85	°C
T <sub>SLD</sub> <sup>(1)</sup>	Lead Solder Temperature for 10 seconds		260	°C
V <sub>IO</sub>	Input or Output Voltages	–0.3 to 7	V	
V <sub>CC</sub>	Supply Voltage	M48T128Y	–0.3 to 7	V
VCC	VCC Supply voltage		-0.3 to 4.6	
Ι <sub>Ο</sub>	Output Current	20	mA	
PD	Power Dissipation		1	W

Note: 1. Soldering temperature not to exceed 260°C for 10 seconds (total thermal budget not to exceed 150°C for longer than 30 seconds).

CAUTION: Negative undershoots below -0.3V are not allowed on any pin while in the Battery Back-up mode.

#### DC AND AC PARAMETERS

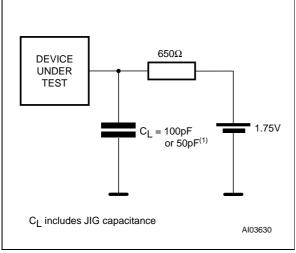
This section summarizes the operating and measurement conditions, as well as the DC and AC characteristics of the device. The parameters in the following DC and AC Characteristic tables are derived from tests performed under the Measurement Conditions listed in the relevant tables. Designers should check that the operating conditions in their projects match the measurement conditions when using the quoted parameters.

#### **Table 3. Operating and AC Measurement Conditions**

Parameter	M48T128Y	M48T128V	Unit
Supply Voltage (V <sub>CC</sub> )	4.5 to 5.5	3.0 to 3.6	V
Ambient Operating Temperature (T <sub>A</sub> )	0 to 70	0 to 70	°C
Load Capacitance (CL)	100	50	pF
Input Rise and Fall Times	≤ 5	≤ 5	ns
Input Pulse Voltages	0 to 3	0 to 3	V
Input and Output Timing Ref. Voltages	1.5	1.5	V

Note: Output Hi-Z is defined as the point where data is no longer driven.

#### Figure 5. AC Testing Load Circuit



Note: 50pF for M48T128V.

#### **Table 4. Capacitance**

\$ Symbol			Max	Unit
C <sub>IN</sub>	Input Capacitance		20	pF
C <sub>IO</sub> <sup>(3)</sup>	Input / Output Capacitance		20	pF

Note: 1. Effective capacitance measured with power supply at 5V. Sampled only, not 100% tested.

2. At 25°C, f = 1MHz.

3. Outputs deselected.

#### **Table 5. DC Characteristics**

			M48T128Y -70		M48T128V 85		Unit
Symbol	Parameter	Test Condition <sup>(1)</sup>					
			Min	Max	Min	Max	
ILI	Input Leakage Current	$0V \leq V_{IN} \leq V_{CC}$		±2		±2	μA
I <sub>LO</sub> <sup>(2)</sup>	Output Leakage Current	$0V \le V_{OUT} \le V_{CC}$		±2		±2	μA
Icc	Supply Current	Outputs open		95		50	mA
I <sub>CC1</sub>	Supply Current (Standby) TTL	$\overline{E} = V_{IH}$		8		4	mA
I <sub>CC2</sub>	Supply Current (Standby) CMOS	$\overline{E} = V_{CC} - 0.2V$		4		3	mA
V <sub>IL</sub>	Input Low Voltage		-0.3	0.8	-0.3	0.4	V
V <sub>IH</sub>	Input High Voltage		2.2	V <sub>CC</sub> + 0.3	2.2	$V_{CC} + 0.3$	V
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 2.1mA		0.4		0.4	V
V <sub>OH</sub>	Output High Voltage	$I_{OH} = -1mA$	2.4		2.2		V

Note: 1. Valid for Ambient Operating Temperature: T<sub>A</sub> = 0 to 70°C; V<sub>CC</sub> = 4.5 to 5.5V or 3.0 to 3.6V (except where noted). 2. Outputs deselected.

#### **OPERATION MODES**

Figure 4, page 4 illustrates the static memory array and the quartz controlled clock oscillator. The clock locations contain the year, month, date, day, hour, minute, and second in 24 hour BCD format. Corrections for 28, 29 (leap year - valid until 2100), 30, and 31 day months are made automatically. Byte 1FFF8h is the clock control register. This byte controls user access to the clock information and also stores the clock calibration setting. The seven clock bytes (1FFFFh - 1FFF8h) are not the actual clock counters, they are memory locations consisting of BiPORT<sup>™</sup> READ/WRITE memory cells within the static RAM array. The M48T128Y/V includes a clock control circuit which updates the clock bytes with current information once per sec-

Tabla	6	Operating Mag	loc
rable	о.	Operating Mod	ies

Mode	Vcc	Ē	G	w	DQ0-DQ7	Power
Deselect		VIH	Х	Х	High Z	Standby
WRITE	4.5 to 5.5V	VIL	Х	V <sub>IL</sub>	D <sub>IN</sub>	Active
READ	or 3.0 to 3.6V	VIL	VIL	VIH	D <sub>OUT</sub>	Active
READ		VIL	VIH	V <sub>IH</sub>	High Z	Active
Deselect	$V_{\text{SO}}$ to $V_{\text{PFD}}  (\text{min})^{(1)}$	Х	Х	Х	High Z	CMOS Standby
Deselect	$\leq V_{SO}^{(1)}$	Х	Х	Х	High Z	Battery Back-up Mode

Note: X = V<sub>IH</sub> or V<sub>IL</sub>; V<sub>SO</sub> = Battery Back-up Switchover Voltage. 1. See Table 10, page 11 for details.

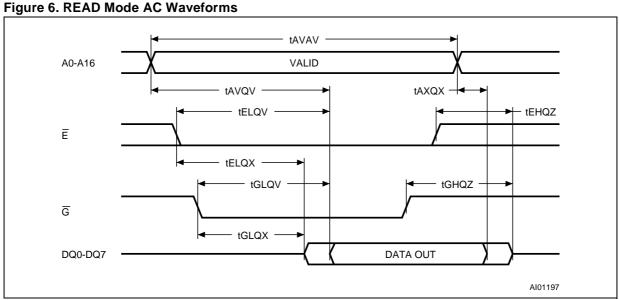


#### **READ Mode**

<u>The M48T128Y/V is in the READ Mode whenever</u> W (WRITE Enable) is high and E (Chip Enable) is low. The unique address specified by the 17 Address Inputs defines which one of the 131,072 bytes of data is to be accessed.

Valid data will be available at the Data I/O pins within  $t_{AVQV}$  (Address Access Time) after the last address input signal is stable, providing the E and G access times are also satisfied. If the E and G access times are not met, valid data will be avail-

able after the latter of the Chip Enable Access Times ( $t_{ELQV}$ ) or Output Enable Access Time ( $t_{GLQV}$ ). The state of the eight three-state Data I/O signals is controlled by E and G. If the outputs are activated before  $t_{AVQV}$ , the data lines will be driven to an indeterminate state until  $t_{AVQV}$ . If the Address Inputs are changed while E and G remain active, output data will remain valid for  $t_{AXQX}$  (Output Data Hold Time) but will go indeterminate until the next Address Access.



Note:  $\overline{WE} = High$ .

		M481	Г128Ү	M481		
Symbol	Parameter <sup>(1)</sup>	-	-70		-85	
		Min	Max	Min	Max	
t <sub>AVAV</sub>	READ Cycle Time	70		85		ns
t <sub>AVQV</sub>	Address Valid to Output Valid		70		85	ns
t <sub>ELQV</sub>	Chip Enable Low to Output Valid		70		85	ns
t <sub>GLQV</sub>	Output Enable Low to Output Valid		40		55	ns
t <sub>ELQX</sub> <sup>(2)</sup>	Chip Enable Low to Output Transition	5		5		ns
t <sub>GLQX</sub> <sup>(2)</sup>	Output Enable Low to Output Transition	5		5		ns
t <sub>EHQZ</sub> <sup>(2)</sup>	Chip Enable High to Output Hi-Z		25		30	ns
t <sub>GHQZ</sub> <sup>(2)</sup>	Output Enable High to Output Hi-Z		25		30	ns
t <sub>AXQX</sub>	Address Transition to Output Transition	10		5		ns

Note: 1. Valid for Ambient Operating Temperature:  $T_A = 0$  to 70°C;  $V_{CC} = 4.5$  to 5.5V or 3.0 to 3.6V (except where noted).

2. C<sub>L</sub> = 5pF.

#### WRITE Mode

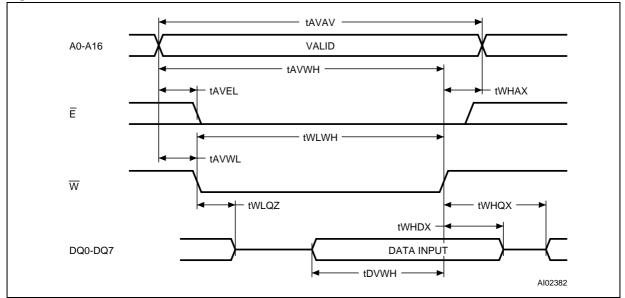
<u>The M48T128Y/V is in the WRITE Mode whenever</u> W (WRITE Enable) and  $\vec{E}$  (Chip Enable) are low state after the address inputs are stable.

The start of a WRITE is <u>referenced</u> from the latter occurring falling edge of W or E. A <u>WRITE</u> is terminated by the earlier rising edge of W or E. The addresses must be held valid throughout the cycle. E or W must return high for a minimum of  $t_{EHAX}$  from

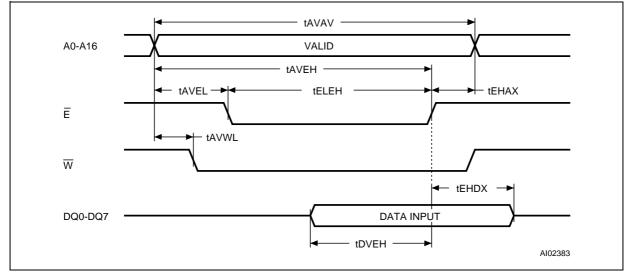
Chip Enable or  $t_{WHAX}$  from WRITE Enable prior to the initiation of another READ or WRITE cycle. Data-in must be valid  $t_{DVWH}$  prior to the end <u>of</u> WRITE and remain valid for  $t_{WHDX}$  afterward. G should be kept high during WRITE cycles to avoid bus contention; although, <u>if</u> the <u>output bus</u> has been activated by a low on E an<u>d</u> G a low on W will disable the outputs  $t_{WLQZ}$  after W falls.

**A7** 

Figure 7. WRITE Enable Controlled, WRITE AC Waveform



#### Figure 8. Chip Enable Controlled, WRITE AC Waveforms



		M48 <sup>-</sup>	T128Y	M481	128V	
Symbol	Parameter <sup>(1)</sup>	-	70	-85		Unit
		Min	Max	Min	Мах	
t <sub>AVAV</sub>	WRITE Cycle Time	70		85		ns
tAVWL	Address Valid to WRITE Enable Low	0		0		ns
t <sub>AVEL</sub>	Address Valid to Chip Enable Low	0		0		ns
t <sub>WLWH</sub>	WRITE Enable Pulse Width	50		60		ns
<b>t</b> ELEH	Chip Enable Low to Chip Enable 1 High	55		65		ns
t <sub>WHAX</sub>	WRITE Enable High to Address Transition	5		5		ns
t <sub>EHAX</sub>	Chip Enable High to Address Transition	10		15		ns
t <sub>DVWH</sub>	Input Valid to WRITE Enable High	30		35		ns
t <sub>DVEH</sub>	Input Valid to Chip Enable High	30		35		ns
t <sub>WHDX</sub>	WRITE Enable High to Input Transition	5		5		ns
t <sub>EHDX</sub>	Chip Enable High to Input Transition	10		15		ns
t <sub>WLQZ</sub> <sup>(2,3)</sup>	WRITE Enable Low to Output Hi-Z		25		30	ns
t <sub>AVWH</sub>	Address Valid to WRITE Enable High	60		70		ns
t <sub>AVEH</sub>	Address Valid to Chip Enable High	60		70		ns
t <sub>WHQX</sub> <sup>(2,3)</sup>	WRITE Enable High to Output Transition	5		5		ns

#### **Table 8. WRITE Mode AC Characteristics**

Note: 1. Valid for Ambient Operating Temperature: T<sub>A</sub> = 0 to 70°C; V<sub>CC</sub> = 4.5 to 5.5V or 3.0 to 3.6V (except where noted).
2. C<sub>L</sub> = 5pF.
3. If E goes low simultaneously with W going low, the outputs remain in the high impedance state.

#### **Data Retention Mode**

With valid V<sub>CC</sub> applied, the M48T128Y/V operates as a conventional BYTEWIDE™ static RAM. Should the supply voltage decay, the RAM will automatically power-fail deselect, write protecting itself when  $\dot{V}_{CC}$  falls within the  $V_{PFD}$  (max),  $V_{PFD}$ (min) window. All outputs become high impedance, and all inputs are treated as "Don't care."

Note: A power failure during a WRITE cycle may corrupt data at the currently addressed location, but does not jeopardize the rest of the RAM's content. At voltages below VPFD (min), the user can be assured the memory will be in a write protected state, provided the V<sub>CC</sub> fall time is not less than t<sub>F</sub>. The M48T128Y/V may respond to transient noise spikes on  $V_{\mbox{\scriptsize CC}}$  that reach into the deselect window during the time the device is sampling V<sub>CC</sub>. Therefore, decoupling of the power supply lines is recommended.

When  $V_{\mbox{CC}}$  drops below  $V_{\mbox{SO}},$  the control circuit switches power to the internal battery, preserving data and powering the clock. The internal energy source will maintain data in the M48T128Y/V for an accumulated period of at least 10 years at room temperature. As system power rises above V<sub>SO</sub>, the battery is disconnected, and the power supply is switched to external V<sub>CC</sub>. Deselect continues for tREC after VCC reaches VPFD (max).

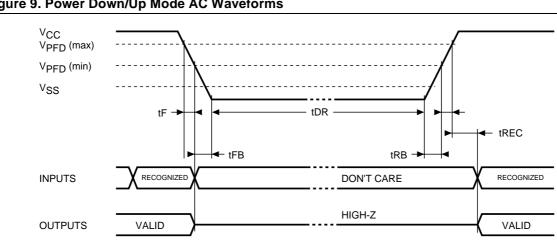


Figure 9. Power Down/Up Mode AC Waveforms

#### Table 9. Power Down/Up AC Characteristics

Symbol	Parameter <sup>(1)</sup>	Min	Max	Unit
t <sub>F</sub> <sup>(2)</sup>	$V_{\text{PFD}}$ (max) to $V_{\text{PFD}}$ (min) $V_{\text{CC}}$ Fall Time	300		μs
t <sub>FB</sub> <sup>(3)</sup>	$V_{\text{PFD}}$ (min) to $V_{\text{SS}}$ $V_{\text{CC}}$ Fall Time	10		μs
t <sub>R</sub>	$V_{\text{PFD}}$ (min) to $V_{\text{PFD}}$ (max) $V_{\text{CC}}$ Rise Time	0		μs
t <sub>RB</sub>	$V_{\text{SS}}$ to $V_{\text{PFD}}$ (min) $V_{\text{CC}}$ Rise Time	1		μs
tREC	V <sub>PFD</sub> (max) to Inputs Recognized	40	200	ms

Note: 1. Valid for Ambient Operating Temperature:  $T_A = 0$  to 70°C;  $V_{CC} = 4.5$  to 5.5V or 3.0 to 3.6V (except where noted).

2. VPFD (max) to VPFD (min) fall time of less than tF may result in deselection/write protection not occurring until 200µs after VCC passes VPFD (min).

3. VPFD (min) to VSS fall time of less than tFB may cause corruption of RAM data.



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Symbol	Parameter <sup>(1,2)</sup>		Min	Тур	Max	Unit
V <sub>PFD</sub>	M4		4.1	4.35	4.5	V
	Power-fail Deselect Voltage M48T128V	2.7	2.9	3.0	V	
Vac		M48T128Y		3.0		V
V <sub>SO</sub>	Battery Back-up Switchover Voltage M48T128V			V <sub>PFD</sub> –100mV		V
t <sub>DR</sub> <sup>(3)</sup>	Expected Data Retention Time		10			YEARS

Table 10. Power Down/Up Trip Points DC Characteristics

Note: 1. All voltages referenced to VSS.

2. Valid for Ambient Operating Temperature: T<sub>A</sub> = 0 to 70°C; V<sub>CC</sub> = 4.5 to 5.5V or 3.0 to 3.6V (except where noted).

3. At 25°C.

#### **CLOCK OPERATIONS**

#### **Reading the Clock**

Updates to the TIMEKEEPER<sup>®</sup> registers should be halted before clock data is read to prevent reading data in transition. The BiPORT<sup>™</sup> TIME-KEEPER cells in the RAM array are only data registers and not the actual clock counters, so updating the registers can be halted without disturbing the clock itself.

Updating is halted when a '1' is written to the READ Bit, D6 in the Control Register (1FFF8h). As long as a '1' remains in that position, updating is halted. After a halt is issued, the registers reflect the count; that is, the day, date, and time that were current at the moment the halt command was issued. All of the TIMEKEEPER registers are updated simultaneously. A halt will not interrupt an update in progress. Updating is within a second after the bit is reset to a '0.'

#### Setting the Clock

Bit D7 of the Control Register (1FFF8h) is the WRITE Bit. Setting the WRITE Bit to a '1,' like the

READ Bit, halts updates to the TIMEKEEPER registers. The user can then load them with the correct day, date, and time data in 24 hour BCD format (see Table 11, page 12). Resetting the WRITE Bit to a '0' then transfers the values of all time registers 1FFFFh-1FFF9h to the actual TIME-KEEPER counters and allows normal operation to resume. After the WRITE Bit is reset, the next clock update will occur one second later.

#### Stopping and Starting the Oscillator

The oscillator may be stopped at any time. If the device is going to spend a significant amount of time on the shelf, the oscillator can be turned off to minimize current drain on the battery. The STOP Bit is located at Bit D7 within 1FFF9h. Setting it to a '1' stops the oscillator. The M48T128Y/V is shipped from STMicroelectronics with the STOP Bit set to a '1.' When reset to a '0,' the M48T128Y/V oscillator starts after one second.

#### Table 11. Register Map

Address				Da	ita		_		Function/Range			
Audress	D7	D6	D5	D4	D3	D2	D1	D0	BCD Format			
1FFFh		10 Y	'ears		Year				Year	00-99		
1FFEh	0	0	0	10 M	Month			Month	01-12			
1FFDh	0	0	10 [	Date	Date			Date	01-31			
1FFCh	0	FT	0	0	0	0 Day			Day	01-07		
1FFBh	0	0	10 H	ours	Hours			Hours	00-23			
1FFAh	0	1	0 Minute	S	Minutes				Minutes	00-59		
1FF9h	ST	1	0 Second	ls	Seconds			Seconds	00-59			
1FF8h	W	R	S		Calibration			Control				

Keys: S = SIGN Bit

R = READ Bit

W = WRITE Bit

ST = STOP Bit

0 = Must be set to '0'

Z = '0' and are Read only

Y = '1' or '0'

#### Calibrating the Clock

The M48T128Y/V is driven by a quartz controlled oscillator with a nominal frequency of 32,768Hz. The devices are factory calibrated at 25°C and tested for accuracy. Clock accuracy will not exceed 35 ppm (parts per million) oscillator frequency error at 25°C, which equates to about  $\pm 1.53$  minutes per month. When the Calibration circuit is properly employed, accuracy improves to better than  $\pm 1/-2$  ppm at 25°C. The oscillation rate of crystals changes with temperature (see Figure 10, page 13). The M48T128Y/V design employs periodic counter correction. The calibration circuit adds or subtracts counts from the oscillator divider circuit at the divide by 128 stage, as shown in Figure 11, page 13.

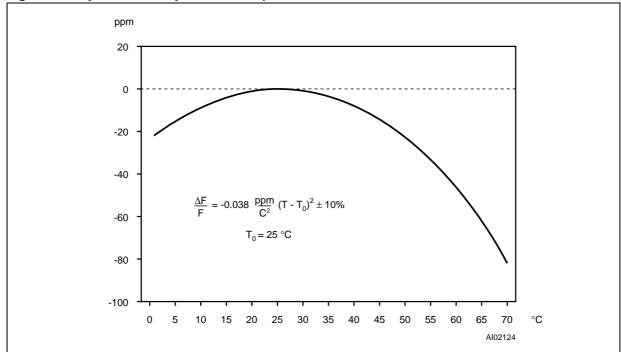
The number of times pulses are blanked (subtracted, negative calibration) or split (added, positive calibration) depends upon the value loaded into the five Calibration bits found in the Control Register. Adding counts speeds the clock up, subtracting counts slows the clock down. The Calibration bits occupy the five lower order bits (D4-D0) in the Control Register 1FFF8h. These bits can be set to represent any value between 0 and 31 in binary form. Bit D5 is a Sign Bit; '1' indicates positive calibration, '0' indicates negative calibration. Calibration occurs within a 64 minute cycle. The first 62 minutes in the cycle may, once per minute, have one second either shortened by 128 or lengthened by 256 oscillator cycles. If a binary '1' is loaded into the register, only the first 2 minutes in the 64 minute cycle will be modified; if a binary 6 is loaded, the first 12 will be affected, and so on. Therefore, each calibration step has the effect of adding 512 or subtracting 256 oscillator cycles for every 125, 829, 120 actual oscillator cycles, that is +4.068 or -2.034 ppm of adjustment per calibration step in the calibration register. Assuming that the oscillator is running at exactly 32,768Hz, each of the 31 increments in the Calibration byte would represent +10.7 or -5.35 seconds per month which corresponds to a total range of +5.5 or -2.75 minutes per month.

One method is available for ascertaining how much calibration a given M48T128Y/V may require. This involves setting the clock, letting it run for a month and comparing it to a known accurate reference and recording deviation over a fixed period of time.

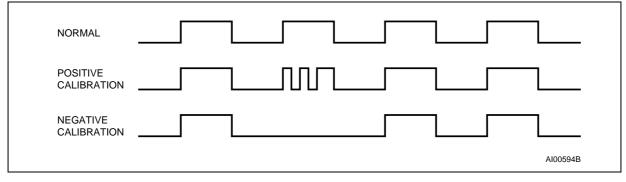
Calibration values, including the number of seconds lost or gained in a given period, can be found in the STMicroelectronics Application Note, "TIMEKEEPER CALIBRATION."

This allows the designer to give the end user the ability to calibrate the clock as the environment requires, even if the final product is packaged in a non-user serviceable enclosure. The designer could provide a simple utility that accesses the Calibration byte. For example, a deviation of 21 seconds slow over a period of 30 days would indicate a -8 ppm oscillator frequency error, requiring a +2(WR100010) to be loaded into the Calibration Byte for correction.

Figure 10. Crystal Accuracy Across Temperature



## Figure 11. Clock Calibration

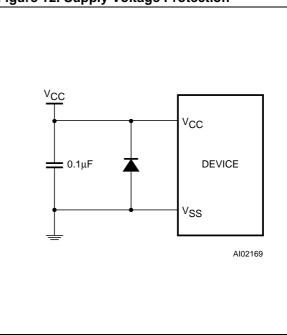


#### V<sub>CC</sub> Noise And Negative Going Transients

 $I_{CC}$  transients, including those produced by output switching, can produce voltage fluctuations, resulting in spikes on the  $V_{CC}$  bus. These transients can be reduced if capacitors are used to store energy which stabilizes the  $V_{CC}$  bus. The energy stored in the bypass capacitors will be released as low going spikes are generated or energy will be absorbed when overshoots occur. A ceramic bypass capacitor value of  $0.1\mu F$  (as shown in Figure 12) is recommended in order to provide the needed filtering.

In addition to transients that are caused by normal SRAM operation, power cycling can generate negative voltage spikes on V<sub>CC</sub> that drive it to values below V<sub>SS</sub> by as much as one volt. These negative spikes can cause data corruption in the SRAM while in battery backup mode. To protect from these voltage spikes, it is recommended to connect a schottky diode from V<sub>CC</sub> to V<sub>SS</sub> (cathode connected to V<sub>CC</sub>, anode to V<sub>SS</sub>). Schottky diode 1N5817 is recommended for through hole and MBRS120T3 is recommended for surface mount.

#### Figure 12. Supply Voltage Protection



**A7** 

#### PART NUMBERING

#### Table 12. Ordering Information Scheme

Example:	M48T	128Y	-70	PM	1	TR
Device Type						
M48T						
Supply Voltage and Write Protect Voltage						
$128Y = V_{CC} = 4.5 \text{ to } 5.5V; V_{PFD} = 4.1 \text{ to } 4.5V$						
$128V^{(1)} = V_{CC} = 3.0$ to 3.6V; $V_{PFD} = 2.7$ to 3.0V						
Speed						
-70 = 70ns (128Y)						
-85 = 85ns (128V)						
Package						
PM = PMDIP32						
Temperature Range						
1 = 0 to 70°C						
Shipping Method for SOIC						

blank = Tubes

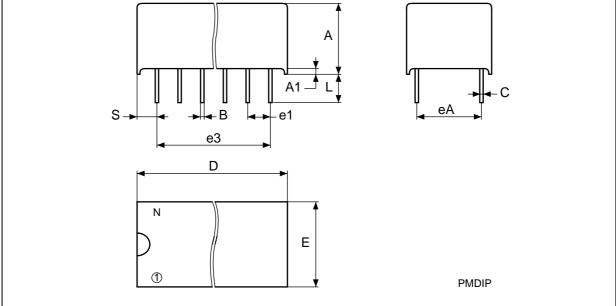
TR = Tape & Reel

Note: 1. Contact Local Sales Office

For a list of available options (e.g., Speed, Package) or for further information on any aspect of this device, please contact the ST Sales Office nearest you.

#### PACKAGE MECHANICAL INFORMATION

# Figure 13. PMDIP32 – 32-pin Plastic Module DIP, Package Outline



Note: Drawing is not to scale.

#### Table 13. PMDIP32 – 32-pin Plastic Module DIP, Package Mechanical Data

	· ·	mm	· 0	İ	inches	
Symb					Inches	
Cyms	Тур	Min	Max	Тур	Min	Max
A		9.27	9.52		0.365	0.375
A1		0.38	-		0.015	-
В		0.43	0.59		0.017	0.023
С		0.20	0.33		0.008	0.013
D		42.42	43.18		1.670	1.700
E		18.03	18.80		0.710	0.740
e1		2.29	2.79		0.090	0.110
e3		34.29	41.91		1.350	1.650
eA		14.99	16.00		0.590	0.630
L		3.05	3.81		0.120	0.150
S		1.91	2.79		0.075	0.110
N		32			32	

#### **REVISION HISTORY**

#### Table 14. Document Revision History

Date	Revision Details			
June 1998	First Issue			
01/31/00	Calibrating The Clock Paragraph changed			
03/30/00	Storage Temperature changed (Table 2)			
07/20/01	Reformatted; temperature information added to tables (Table 4, 5, 7, 8, 9, 10)			
09/21/01	Corrected speed grade in ordering information			
05/23/02	Add countries to disclaimer; add marketing status			



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